

# DDR5 SDRAM SODIMM Core

## Product Description

This specification defines the electrical and mechanical requirements for 262-pin, 1.1V ( $V_{DD}$ ) small outline, double data rate, synchronous DRAM dual in-line memory modules (DDR5 SDRAM SODIMMs). These DDR5 SODIMMs are intended for use as main memory when installed in PCs, laptops, and other systems. Some specifications are part number-specific; refer to the module data sheet addendum of the specific Micron part number (MPN) for the complete specification.

## Features

- DDR5 functionality and operations supported as defined in the component data sheet
- 262-pin SODIMM
- Sideband access with I3C-basic/I2C support
- Two independent I/O sub channels for increased bandwidth
- Gold edge contacts
- Halogen-free
- Fly-by topology
- Terminated clock, control and command/address
- DDR command/address bus to RCD
- Gold edge contacts
- Halogen-free
- Fly-by topology
- Terminated clock, control and command/address bus

**Table 1: Product Family Attributes**

Parameter	Options	Notes
DIMM organization	x64, x72 ECC	Two 32-bit sub-channels (non-ECC), two 36-bit sub-channels (ECC)
DIMM dimensions (nominal)	69.6mm x 30mm	Refer to Module Dimensions
Pin count	262	
DDR5 SDRAM densities supported	16Gb, 24Gb, 32Gb, 64Gb	78/82-ball FBGA package for x8 devices, 102-ball FBGA package for x16 devices
Capacity	8GB-128GB	
DDR5 SDRAM width	x8, x16	
Data transfer rate	PC5-4800 to PC5-5600	Refer to Key Timing Parameters
Serial presence detect hub with temperature sensor	1024 byte	
Voltage (external supply, nominal)	V <sub>IN_Bulk</sub> : 5V	Bulk input DC supply voltage from system
Voltage (PMIC output)	V <sub>DD</sub> : 1.1V	Supply voltage from PMIC
	V <sub>DDQ</sub> : 1.1V	I/O Supply voltage from PMIC
	V <sub>PP</sub> : 1.8V	Pump voltage from PMIC
	1.8V LDO output	From PMIC to HUB
	1.0V LDO output	
Interface	1.1V signaling	
DRAM Operating temperature	T <sub>OPER</sub> = 0 to 95°C	Refer to Thermal Characteristics

**Table 2: Key Timing Parameters<sup>1</sup>**

Speed Bins	PC5	Data Rate (MT/s)												t <sub>AA</sub> (ns)	t <sub>RCD</sub> (ns)	t <sub>RP</sub> (ns)	t <sub>RC</sub> (ns)
		50	46	42	40	38	36	34	32	30	28	26	22				
5600B	5600	5600	5600/5200	5200	4800/4400	–	4400/4000	–	4000/3600	3600	3200	3200	2100	16.000	16.000	16.000	48.000
5200B	5200	–	5200	5200	4800/4400	–	4400/4000	–	4000/3600	3600	3200	3200	2100	16.000	16.000	16.000	48.000
4800B	4800	–	–	4800	4800/4400	–	4400/4000	–	4000/3600	3600	3200	3200	2100	16.000	16.000	16.000	48.000

Notes: 1. t<sub>AA</sub>, t<sub>RCD</sub>, t<sub>RP</sub> and t<sub>RC</sub> values represent the tightest capability across all supported data rates and CL combinations. Refer to component data sheet Speed Bin Tables for details.

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## General Description

High-speed DDR5 SDRAM modules use DDR5 SDRAM devices with four or eight internal memory bank groups. DDR5 SDRAM modules utilizing 4- and 8-bit-wide DDR5 SDRAM devices have eight internal bank groups consisting of four memory banks each, providing a total of 32 banks. 16-bit-wide DDR5 SDRAM devices have four internal bank groups consisting of four memory banks each, providing a total of sixteen banks. DDR5 SDRAM modules benefit from DDR5 SDRAM's use of an 16n-prefetch architecture with an interface designed to transfer two data words per clock cycle at the I/O pins. A single READ or WRITE operation for the DDR5 SDRAM effectively consists of a single 16n-bit-wide, eight-clock data transfer at the internal DRAM core and sixteen corresponding n-bit-wide, one-half-clock-cycle data transfers at the I/O pins.

DDR5 modules use two sets of differential signals (DQS<sub>t</sub> and DQS<sub>c</sub>) to capture data, and CK<sub>t</sub> and CK<sub>c</sub> to capture commands, addresses, and control signals. Differential clocks and data strobes ensure exceptional noise immunity for these signals and provide precise crossing points to capture input signals.

## Fly-By Topology

DDR5 modules use faster clock speeds than earlier DDR technologies, making signal quality more important than ever. For improved signal quality, the clock, control, command, and address buses have been routed in a fly-by topology, where each clock, control, command, and address pin on each DRAM is connected to a single trace and terminated (rather than a tree structure, where the termination is off the module near the connector). Inherent to fly-by topology, the timing skew between the clock and DQS signals can be accounted for by using the write-leveling feature of DDR5.

## Pin Assignments

The pin assignment table below is a comprehensive list of all possible pin assignments for DDR5 SODIMM modules. Certain pins may not apply for a specific part number. Refer to the functional block diagram in the module data sheet addendum for a specific MPN.

**Table 3: Pin Assignments**

262-Pin DDR5 SODIMM Front						262-Pin DDR5 SODIMM Back					
Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol
1	VIN_BULK	89	V <sub>SS</sub>	175	CB3_B	2	HSA	90	V <sub>SS</sub>	176	CB2_B
3	VIN_BULK	91	DQ30_A	177	V <sub>SS</sub>	4	HSCL	92	DQ31_A	178	V <sub>SS</sub>
5	RFU	93	V <sub>SS</sub>	179	DQ0_B	6	HSDA	94	V <sub>SS</sub>	180	DQ1_B
7	PWR_GOOD	95	CB0_A	181	V <sub>SS</sub>	8	PWR_EN	96	CB1_A	182	V <sub>SS</sub>
9	V <sub>SS</sub>	97	V <sub>SS</sub>	183	DQ2_B	10	V <sub>SS</sub>	98	V <sub>SS</sub>	184	DQ3_B
11	DQ0_A	99	CB2_A	185	V <sub>SS</sub>	12	DQ1_A	100	DQS4_A_c	186	V <sub>SS</sub>
13	V <sub>SS</sub>	101	V <sub>SS</sub>	187	DM0_B_n	14	V <sub>SS</sub>	102	DQS4_A_t	188	DQS0_B_c
15	DQ2_A	103	CB3_A	189	V <sub>SS</sub>	16	DQ3_A	104	V <sub>SS</sub>	190	DQS0_B_t
17	V <sub>SS</sub>	105	V <sub>SS</sub>	191	DQ4_B	18	V <sub>SS</sub>	106	CS0_A_n	192	V <sub>SS</sub>
19	DM0_A_n	107	CA0_A	193	V <sub>SS</sub>	20	DQS0_A_c	108	ALERT_n	194	DQ5_B
21	V <sub>SS</sub>	109	CA1_A	195	DQ6_B	22	DQS0_A_t	110	CS1_A_n	196	V <sub>SS</sub>
23	DQ4_A	111	V <sub>SS</sub>	197	V <sub>SS</sub>	24	V <sub>SS</sub>	112	V <sub>SS</sub>	198	DQ7_B
25	V <sub>SS</sub>	113	CA2_A	199	DQ8_B	26	DQ5_A	114	CA3_A	200	V <sub>SS</sub>
27	DQ6_A	115	CA4_A	201	V <sub>SS</sub>	28	V <sub>SS</sub>	116	CA5_A	202	DQ9_B
29	V <sub>SS</sub>	117	V <sub>SS</sub>	203	DQ10_B	30	DQ7_A	118	V <sub>SS</sub>	204	V <sub>SS</sub>



## 262-Pin DDR5 SODIMM Core Pin Assignments

**Table 3: Pin Assignments (Continued)**

262-Pin DDR5 SODIMM Front						262-Pin DDR5 SODIMM Back					
Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol
31	DQ8_A	119	CA6_A	205	V <sub>SS</sub>	32	V <sub>SS</sub>	120	CA7_A	206	DQ11_B
33	V <sub>SS</sub>	121	CA8_A	207	DQS1_B_c	34	DQ09_A	122	CA9_A	208	V <sub>SS</sub>
35	DQ10_A	123	V <sub>SS</sub>	209	DQS1_B_t	36	V <sub>SS</sub>	124	V <sub>SS</sub>	210	DM1_B_n
37	V <sub>SS</sub>	125	CA10_A	211	V <sub>SS</sub>	38	DQ11_A	126	CA11_A	212	V <sub>SS</sub>
39	DQS1_A_c	KEY		213	DQ12_B	40	V <sub>SS</sub>	KEY		214	DQ13_B
41	DQS1_A_t	127	CA12_A	215	V <sub>SS</sub>	42	DM1_A_n	128	RFU	216	V <sub>SS</sub>
43	V <sub>SS</sub>	129	V <sub>SS</sub>	217	DQ14_B	44	V <sub>SS</sub>	130	V <sub>SS</sub>	218	DQ15_B
45	DQ12_A	131	CK0_A_t	219	V <sub>SS</sub>	46	DQ13_A	132	CK1_A_t	220	V <sub>SS</sub>
47	V <sub>SS</sub>	133	CK0_A_c	221	DQ16_B	48	V <sub>SS</sub>	134	CK1_A_c	222	DQ17_B
49	DQ14_A	135	V <sub>SS</sub>	223	V <sub>SS</sub>	50	DQ15_A	136	V <sub>SS</sub>	224	V <sub>SS</sub>
51	V <sub>SS</sub>	137	CK0_B_t	225	DQ18_B	52	V <sub>SS</sub>	138	CK1_B_t	226	DQ19_B
53	DQ16_A	139	CK0_B_c	227	V <sub>SS</sub>	54	DQ17_A	140	CK1_B_c	228	V <sub>SS</sub>
55	V <sub>SS</sub>	141	V <sub>SS</sub>	229	DM2_B_n	56	V <sub>SS</sub>	142	V <sub>SS</sub>	230	DQS2_B_c
57	DQ18_A	143	RFU	231	V <sub>SS</sub>	58	DQ19_A	144	CA12_B	232	DQS2_B_t
59	V <sub>SS</sub>	145	CA11_B	233	DQ20_B	60	V <sub>SS</sub>	146	CA10_B	234	V <sub>SS</sub>
61	DM2_A_n	147	V <sub>SS</sub>	235	V <sub>SS</sub>	62	DQS2_A_c	148	V <sub>SS</sub>	236	DQ21_B
63	V <sub>SS</sub>	149	CA9_B	237	DQ22_B	64	DQS2_A_t	150	CA8_B	238	V <sub>SS</sub>
65	DQ20_A	151	CA7_B	239	V <sub>SS</sub>	66	V <sub>SS</sub>	152	CA6_B	240	DQ23_B
67	V <sub>SS</sub>	153	V <sub>SS</sub>	241	DQ24_B	68	DQ21_A	154	V <sub>SS</sub>	242	V <sub>SS</sub>
69	DQ22_A	155	CA5_B	243	V <sub>SS</sub>	70	V <sub>SS</sub>	156	CA4_B	244	DQ25_B
71	V <sub>SS</sub>	157	CA3_B	245	DQ26_B	72	DQ23_A	158	CA2_B	246	V <sub>SS</sub>
73	DQ24_A	159	V <sub>SS</sub>	247	V <sub>SS</sub>	74	V <sub>SS</sub>	160	V <sub>SS</sub>	248	DQ27_B
75	V <sub>SS</sub>	161	CS0_B_n	249	DQS3_B_c	76	DQ25_A	162	CA1_B	250	V <sub>SS</sub>
77	DQ26_A	163	RESET_n	251	DQS3_B_t	78	V <sub>SS</sub>	164	CA0_B	252	DM3_B_n
79	V <sub>SS</sub>	165	CS1_B_n	253	V <sub>SS</sub>	80	DQ27_A	166	V <sub>SS</sub>	254	V <sub>SS</sub>
81	DQS3_A_c	167	V <sub>SS</sub>	255	DQ28_B	82	V <sub>SS</sub>	168	CB0_B	256	DQ29_B
83	DQS3_A_t	169	DQS4_B_c	257	V <sub>SS</sub>	84	DM3_A_n	170	V <sub>SS</sub>	258	V <sub>SS</sub>
85	V <sub>SS</sub>	171	DQS4_B_t	259	DQ30_B	86	V <sub>SS</sub>	172	CB1_B	260	DQ31_B
87	DQ28_A	173	V <sub>SS</sub>	261	V <sub>SS</sub>	88	DQ29_A	174	V <sub>SS</sub>	262	V <sub>SS</sub>

## Pin Descriptions

The pin description table below is a comprehensive list of all possible pins for DDR5 UDIMM/SODIMM devices. All pins listed may not be supported on a specific module. See Functional Block Diagram in the MPN-specific addendum for pins applicable to a given module.

**Table 4: Pin Descriptions**

Symbol	Type	I/O Level	Description
CK[1:0]_A_t, CK[1:0]_B_t, CK[1:0]_A_c, CK[1:0]_B_c	Input	V <sub>DDQ</sub>	<b>SDRAM Clocks</b> CK_t and CK_c are differential clock inputs. All address and control input signals are sampled on the crossing of the positive edge of CK_t and negative edge of CK_c.
CA[12:0]_A CA[12:0]_B			
CS[1:0]_A CS[1:0]_B	Input	V <sub>DDQ</sub>	<b>Chip Select:</b> All commands are masked when CS_n is registered HIGH. CS_n provides for external rank selection on systems with multiple ranks. CS_n is considered part of the command code. CS_n is also used to enter and exit the parts from power down mode and self refresh mode. While not in self refresh mode the CS_n input buffer operates with the same ODT and V <sub>REF</sub> parameters as configured by the CA_ODT strap setting or mode register. When in self refresh, the CS_n is a CMOS rail-to-rail signal with DC HIGH and LOW at 80% and 20% of V <sub>DD</sub> .
ALERT_n	Output	V <sub>DDQ</sub>	<b>Alert:</b> If there is an error in CRC, then ALERT_n drives LOW for the period time interval and returns HIGH. During connectivity test mode, this pin functions as an input. Usage of this signal is system-dependent. In the case where this pin is not connected, ALERT_n must be bonded to V <sub>DDQ</sub> on the system board.
RESET_n	CMOS Input	V <sub>DDQ</sub>	<b>Active Low Asynchronous Reset:</b> Reset is active when RESET_n is LOW, and inactive when RESET_n is HIGH. RESET_n must be HIGH during normal operation. RESET_n is a CMOS rail-to-rail signal with DC HIGH and LOW at 80% and 20% of V <sub>DDQ</sub> .
PWR_GOOD	Input Output	V <sub>DDQ</sub>	<b>Power Good Indicator:</b> Open drain output. The PMIC ensures this pin HIGH when VIN_Bulk input supply, as well as all enabled output buck regulators and all LDO regulators tolerance threshold is maintained as configured in the appropriate register. The PMIC drives this pin LOW when VIN_Bulk input goes below the threshold or when any of the enabled output buck regulator exceeds the thresholds configured in the appropriate register or when any LDO output regulator exceeds the threshold configured in the appropriate register. As an input, the PMIC disables its output regulator when this pin is LOW. The LDO outputs remain on.
HSCL	Input	VOUT_1.8V or VOUT_1.0V	<b>Host Sideband Bus Clock:</b> Bus clock used to strobe data into HUB device. When open drain, a pull-up resistor is required on the system motherboard.
HSDA	Input/Output	VOUT_1.8V or VOUT_1.0V	<b>Host Sideband Bus Data:</b> I2C/I3C-Basic data. When open drain, a pull-up resistor is required on the system motherboard.

**Table 4: Pin Descriptions (Continued)**

Symbol	Type	I/O Level	Description
HSA	Input	GND	<b>Host Sideband Bus Device ID:</b> Address input to a hub or other client device to distinguish between identical devices in the I3C basic address range. Tied to GND, HSA has different resistor values on the motherboard to identify DIMM slot address. Refer to the SPD Hub spec for more information.
DQ[31:0]_A DQ[31:0]_B	Input/ Output	V <sub>DDQ</sub>	<b>Data Input/Output:</b> Bidirectional data bus. If CRC is enabled via the mode register, then CRC code is added at the end of data burst. Any DQ from DQ0–DQ3 may indicate the internal V <sub>REF</sub> level during test via mode register setting MR4 A4 = HIGH. Refer to the vendor-specific data sheets to determine which DQ is used.
CB[3:0]_A CB[3:0]_B	Input/ Output	V <sub>DDQ</sub>	<b>ECC Check Bits Input/Output:</b> Bidirectional data bus. Only applicable on ECC SODIMM (SOEDIMM) or UDIMM (EUDIMM).
DQS[4:0]_A_t DQS[4:0]_B_t DQS[4:0]_A_c DQS[4:0]_B_c	Input/ Output	V <sub>DDQ</sub>	<b>Data Strobe:</b> Output with read data, input with write data. Edge-aligned with read data, centered in write data. The data strobe DQS_t is paired with differential signals DQS_c, respectively, to provide differential pair signaling to the system during reads and writes. DDR5 SDRAM only supports differential data strobe. It does not support single-ended strobe.
DM[3:0]_A_n DM[3:0]_B_n	Input	V <sub>DDQ</sub>	<b>Input Data Mask:</b> DM_n is an input mask signal for write data. Input data is masked when DM_n is sampled LOW coincident with that input data during a write access. DM_n is sampled on both edges of DQS. DM function is shared with TDQS on x8 devices. The function of DM_n is enabled by MR5:OP[5] = 1. Refer to Micron DDR5 component data sheet specification for further detail.
VIN_BULK	Supply		<b>External Power Supply:</b> 5V, 4.25V (min), 5.5V (max)
PWR_EN	Input		<b>PMIC Enable:</b> When this pin is HIGH, the PMIC turns on the regulator. When this pin is LOW, the PMIC turns off the regulator. This signal is connected to the PMIC's VR_EN pin.
V <sub>SS</sub>	Supply		Ground
RFU			Reserved for future use. No on DIMM electrical connection is present.
NC			<b>No connect:</b> No internal electrical connection is present.
NF			<b>No function:</b> May have internal connection present, but has no function.

## Address Mapping to DRAM

### Address Mirroring

DDR5 SDRAM has an MIR input pin. This pin is strapped (connected) to  $V_{SS}$  or  $V_{DDQ}$  on the PCB. This pin is used to inform the SDRAM device that it is being configured for mirrored mode vs. standard mode. With the MIR pin strapped to  $V_{DDQ}$ , the SDRAM internally swaps even-numbered CA with the next higher odd number CA. Normally, the MIR pin must be strapped to  $V_{SS}$  if no CA mirror is required. The following table illustrates how the edge connector pin maps to the DRAM physical CA pins and internal CA function.

**Table 5: Address Mirroring**

Edge Connector Pin	Unmirrored DRAM (MIR = $V_{SS}$ ) <sup>1</sup>		Mirrored DRAM (MIR = $V_{DDQ}$ ) <sup>2</sup>	
	Physical Pin Connected	Internal Function	Physical Pin Connected	Internal Function
CA0	CA0	CA0	CA1	CA0
CA1	CA1	CA1	CA0	CA1
CA2	CA2	CA2	CA3	CA2
CA3	CA3	CA3	CA2	CA3
CA4	CA4	CA4	CA5	CA4
CA5	CA5	CA5	CA4	CA5
CA6	CA6	CA6	CA7	CA6
CA7	CA7	CA7	CA6	CA7
CA8	CA8	CA8	CA9	CA8
CA9	CA9	CA9	CA8	CA9
CA10	CA10	CA10	CA11	CA10
CA11	CA11	CA11	CA10	CA11
CA12	CA12	CA12	CA13	CA12

Notes: 1. On the side of the DIMM which has the MIR pin strapped to  $V_{SS}$ , the DRAM's CA13 pin is strapped to  $V_{DDQ}$ .  
 2. On the side of the DIMM which has the MIR pin strapped to  $V_{DDQ}$ , the DRAM's CA12 pin is strapped to  $V_{DDQ}$ .



## SPD EEPROM Hub and Integrated Thermal Sensor Operation

### SPD EEPROM Hub Operation

DDR5 SDRAM modules incorporate an SPD EEPROM with hub function (SPD5 Hub) with integrated thermal sensor (TS). The SPD data is stored in a 1024-byte, JEDEC JC-42.4-compliant EEPROM that is arranged as 16 blocks of 64 bytes per block, and each block may optionally be write-protected via software command. The SPD content is aligned with these blocks, as shown in the table below.

Block	Range		Description
0	0~63	0x000~0x03F	Base configuration and DRAM parameters
1	64~127	0x040~0x07F	Base configuration and DRAM parameters
2	128~191	0x080~0x0BF	Reserved for future use
3	192~239	0x0C0~0x0EF	Common Module Parameters -- See annex A.0 for details
	240~255	0x0D0~0x0FF	Standard module parameters -- See annexes A.x for details
4	256~319	0x100~0x13F	Standard module parameters -- See annexes A.x for details
5	320~383	0x140~0x17F	Standard module parameters -- See annexes A.x for details
6	384~447	0x180~0x1BF	Standard module parameters -- See annexes A.x for details
7	448~509	0x1C0~0x1FF	Reserved for future use
	510~511	0x1FE~0x1FF	CRC for SPD bytes 0~509
8	512~575	0x200~0x23F	Manufacturing information
9	576~639	0x240~0x27F	Manufacturing information
10	640~703	0x280~0x2BF	End user programmable
11	704~767	0x2C0~0x2FF	End user programmable
12	768~831	0x300~0x33F	End user programmable
13	832~895	0x340~0x37F	End user programmable
14	896~959	0x380~0x3BF	End user programmable
15	960~1023	0x3C0~0x3FF	End user programmable

The first 640 bytes are programmed by Micron to comply with JEDEC standard JESD400-5, "DDR5 Serial Presence Detect (SPD) Contents." The remaining 384 bytes of storage are available for use by the end user.

The EEPROM resides on a two-wire I3C serial interface, which is also compatible with legacy I2C interface and is not integrated with the memory bus in any manner. It operates as an initiator/target device in the I3C-basic protocol, with all operations synchronized by the serial clock. Transfer rates of up to 12.5 MHz are achievable at 1.0V (NOM).

Micron implements reversible software write protection on DDR5 SDRAM-based modules. This prevents the lower 640 bytes (bytes 0 to 639) from being inadvertently programmed or corrupted. The upper 384 bytes remain available for customer use and are unprotected.



### Integrated Thermal Sensor Operations

The integrated thermal sensor (TS) continuously monitors the temperature of the module PCB and updates the temperature data register. Temperature data may be read from the bus host at any time, which provides the host real-time feedback of the module's temperature. Multiple programmable and read-only temperature registers can be used to create a custom temperature-sensing solution based on system requirements and JEDEC JC-42.2. Refer to the DDR5 SPD5 Hub spec for detailed information on configuring and reading the integrated thermal sensor.

## Power Management Integrated Circuit Operation

The power management integrated circuit (PMIC) is new for DDR5. JEDEC defines the PMIC5100 device for DDR5 UDIMMs and SODIMMs. This operation converts a 5V supply into regulated values for all components on the module. The PMIC5100 has ~10.6W of average output power capability. The PMIC5100 utilizes a unique pinout and 3mm x 4mm FCQFN package. The PMIC also allows the host to monitor voltage and current via the sideband channel. Refer to JEDEC JESD301-2 “PMIC5100 Power Management IC Specification” for full details.

The PMIC5100 has one 5V nominal supply input pin from the card edge through VIN\_Bulk. The PMIC has the ability to regulate lower voltages to the HUB which allows external access to read/configure this device prior to the VR ENABLE command. The VIN\_Bulk supply, after the VR ENABLE command, will supply all regulated voltages to the PMIC and DRAM.

The PMIC allows the DIMM manufacturer to set the target voltage levels for the DRAM and configure the ramp up and ramp down aspects of each power rail. For power up, each voltage rail can be configured in offsets of 2ms increments and for power down in increments of 1ms. Note, there will be independent power planes for all UDIMM and SODIMM layouts. The DRAM will be connected to all three rails ( $V_{DD}$ ,  $V_{DDQ}$  and  $V_{PP}$ ).

The PMIC has a PWR\_GOOD pin, which is an Open Drain and will have an external pull-up. The functionality of the PWR\_GOOD pin is configurable as an input/output pin. When the VIN\_Bulk input reaches valid threshold levels, the PMIC will float PWR\_GOOD pin indicating a successful initialization. At this time the PMIC releases the PWR\_GOOD signal and allows it to float HIGH (external pull-up resistor on the host side will pull it HIGH). At any time thereafter if VIN\_Bulk drops below a set threshold, or any of the regulated supplies fall out of specification, the PMIC will drive the PWR\_GOOD signal LOW to flag the host. The VR ENABLE command or pin, when set HIGH, will enable the regulators which control all DRAM voltages are stable; when set LOW, it will disable all output regulators.

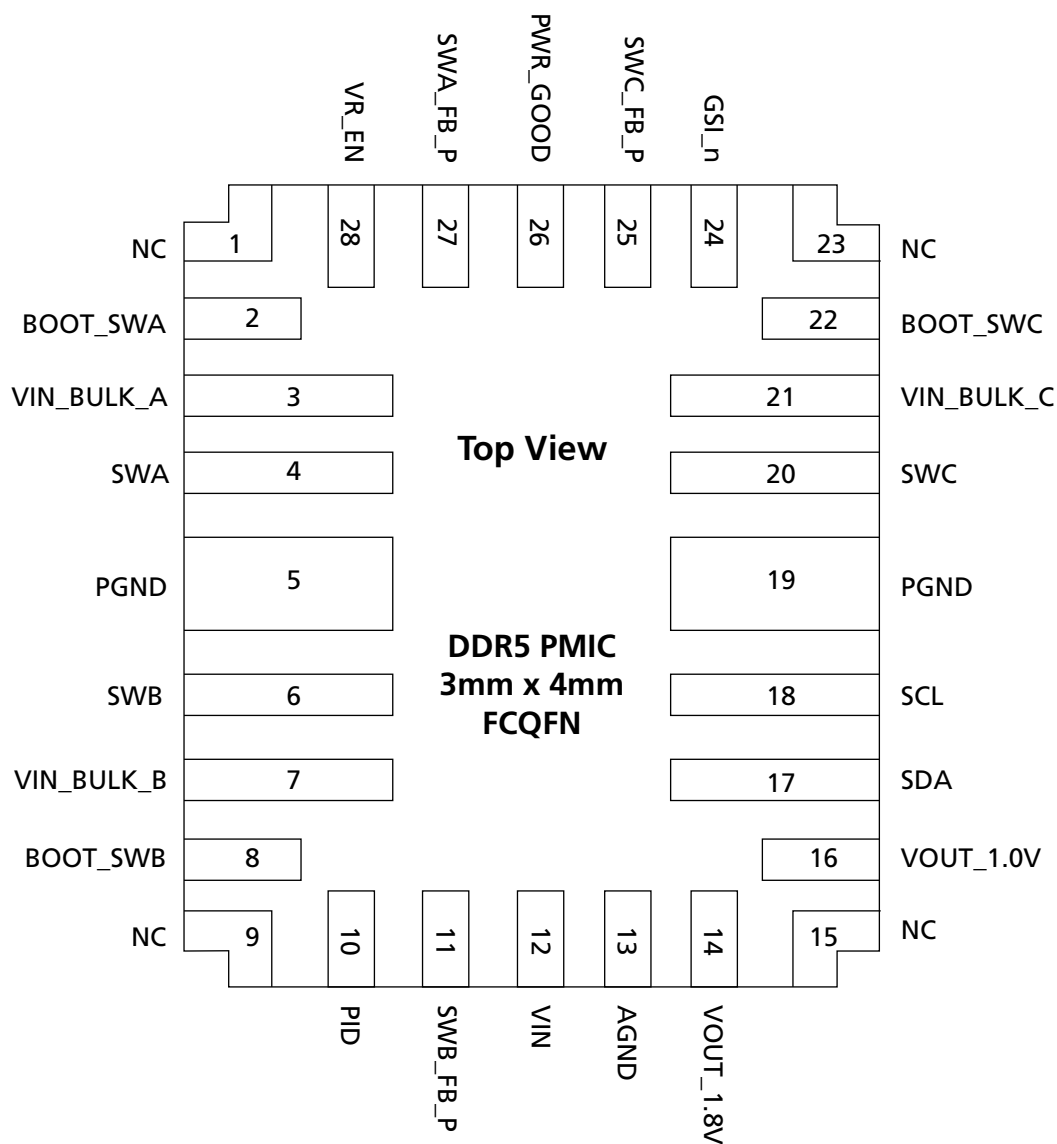
By default, the PMIC powers up in I2C mode, and the host can reconfigure to support I3C-basic if needed. There are three address configurations for the PMIC Address ID (PID), device pin #10. See the table below for options.

**Table 6: PMIC Addressing**

PID Configuration (Pin #10)	PMIC Address ID (PID)			
	Bit 7	Bit 6	Bit 5	Bit 4
Pin to $V_{SS}$	1	0	0	1
Pin to 1.8V	1	1	0	0
Pin Floating	1	0	0	0

The PMIC has multiple sets of registers, primarily the DIMM vendor region and the host region. The vendor region is used to set up the voltage ramps, supply rail values, and threshold settings. The host can also set various registers to flag critical operation conditions and to help debug. After the VR\_ENABLE command is issued, the PMIC can only be programmed in a non-secure mode. If the device remains in a secure mode after the VR\_ENABLE command, the device locks out the ability to change the contents of most registers.

**Figure 1: PMIC Package**



## Thermal Characteristics

**Table 7: DDR5 SDRAM Thermal Characteristics**

Symbol	Parameter/Condition	Value	Units	Notes
$T_C$	DRAM Commercial operating case temperature	0 to 85	°C	1, 2, 3
$T_C$		>85 to 95	°C	1, 2, 3, 4
$T_{OPER}$	DRAM operating temperature range	0 to 95	°C	5, 7, 8
$T_{STG}$	DRAM Non-operating storage temperature	-55 to 100	°C	6

- Notes: 1. Maximum operating case temperature;  $T_C$  is measured in the center of the package.
2. A thermal solution must be designed to ensure the DRAM device does not exceed the maximum  $T_C$  during operation.
3. Device functionality is not guaranteed if the DRAM device exceeds the maximum  $T_C$  during operation.
4. If  $T_C$  exceeds 85°C, the DRAM must be refreshed externally at 2X refresh, which is a 1.95µs interval refresh rate.
5. The refresh rate must double when 85°C <  $T_C$  ≤ 95°C.
6. Storage temperature is defined as the temperature of the top/center of the DRAM and does not reflect the storage temperatures of shipping trays.
7. The normal temperature range specifies the temperatures at which all DRAM specifications will be supported. During operation, the DRAM case temperature must be maintained between 0°C and 85°C under all operating conditions for the commercial offering.
8. For additional information, refer to technical note TN-00-08: "Thermal Applications" available at [micron.com](http://micron.com).

## DDR5 Module Capacitor Operating Temperature

Micron DDR5 SDRAM Modules use X5R capacitors which are limited to a maximum operating case temperature rating of 85°C. All other components on the DIMM meet or exceed the DDR5 SDRAM maximum commercial operating case temperature rating of 95°C. The JEDEC DIMM design specifications require all non-DRAM components are maintained within their respective operating temperature ratings when the case temperature of the DRAMs are at their minimum and maximum specified values.

## DRAM Operating Conditions

AC operating conditions are provided in the DDR5 component data sheets. Please refer to both the DDR5 Product Core Data Sheet and the Die Revision-Specific Data Sheet Addendum. Component specifications are available at [micron.com](https://www.micron.com).

## Design Considerations

### Simulations

Micron memory modules are designed to optimize signal integrity through carefully designed terminations, controlled board impedances, routing topologies, trace length matching, and decoupling. However, good signal integrity starts at the system level. Micron encourages designers to simulate the signal characteristics of the system's memory bus to ensure adequate signal integrity of the entire memory system.

### Power

DRAM operating voltages are generated by an on-DIMM PMIC component. Power to the PMIC is provided through the VIN\_BULK (12V for RDIMMs and LRDIMMs, 5V for UDIMMs and SODIMMs) and 3.3V VIN\_MGMT (LRDIMMs and RDIMMs only) edge connector pins. Designers must account for any system voltage drops at anticipated power levels to ensure the required  $V_{IN}$  supply voltage is maintained.



## SPD EEPROM Hub and Integrated Thermal Sensor Operating Conditions

The thermal sensor continuously monitors the module's temperature and can be read back at any time over the sideband bus shared with the serial presence-detect (SPD) EEPROM. Refer to JESD300-5 SPD5118 device specification for complete details.

### SPD Data

For the latest SPD data, refer to Micron's SPD page: [micron.com/SPD](https://micron.com/SPD).

**Table 8: SPD EEPROM Hub and Integrated Thermal Sensor Electrical Characteristics**

Parameter/Condition	Symbol	Min	Nom	Max	Units
Supply voltage	$V_{DDSPD}$	1.7	1.8	1.98	V
Supply voltage	$V_{DDIO}$	0.95	1.0	1.05	V
Input low voltage	$V_{IL}$	-0.35	–	0.3	V
Input high voltage	$V_{IH}$	0.7	–	3.6	V
Output low voltage	$V_{OL}$	–	–	0.3	V
Output high voltage	$V_{OH}$	0.75	–	–	V
Input leakage current	$I_{LI}$	–	–	±5	μA
Output leakage current	$I_{LO}$	–	–	±5	μA

**Table 9: Temperature Sensor and EEPROM Serial Interface Timing**

Parameter/Condition	Symbol	I2C Mode - Open Drain		I3C Basic Push-Pull		Units
		Min	Max	Min	Max	
Clock frequency	$f_{SCL}$	0.01	1	0	12.5	MHz
Clock pulse width HIGH time	$t_{HIGH}$	260	–	35	–	ns
Clock pulse width LOW time	$t_{LOW}$	500	–	35	–	ns
Detect clock LOW timeout	$t_{TIMEOUT}$	10	50	10	50	ns
SDA rise time	$t_R$	–	120	–	5	ns
SDA fall time	$t_F$	–	120	–	5	ns
Data-in setup time	$t_{SU:DAT}$	50	–	8	–	ns
Data-in hold time	$t_{HD:DI}$	0	–	3	–	ns
Data out hold time	$t_{HD:DAT}$	0.5	350	N/A	N/A	ns
Start condition setup time	$t_{SU:STA}$	260	–	12	–	ns
Start condition hold time	$t_{HD:STA}$	260	–	30	–	ns
Stop condition setup time	$t_{SU:STO}$	260	–	12	–	ns
Time the bus must be free before a new transition can start	$t_{BUF}$	500	–	500	–	ns
Write time	$t_W$	–	5	–	5	ms



## 262-Pin DDR5 SODIMM Core SPD EEPROM Hub and Integrated Thermal Sensor Operating Conditions

**Table 9: Temperature Sensor and EEPROM Serial Interface Timing (Continued)**

Parameter/Condition	Symbol	I2C Mode - Open Drain		I3C Basic Push-Pull		Units
		Min	Max	Min	Max	
Warm power cycle time off	$t_{POFF}$	1	–	1	–	ms
Time from power-on to first command	$t_{INIT}$	10	–	10	–	ms

**Table 10: Absolute Maximum Ratings**

Parameter/Condition	Symbol	Min	Max	Units
Storage temperature	$V_{DDSPD}$	-65	150	°C
Supply voltage	$V_{DDIO}$	-0.5	2.1	V
Supply voltage	$V_{DDSPD}$	-0.5	2.1	V
HSA pin	HSA	-0.5	2.1	V
HSCL, HSDA, LSCL, LSDA pins	HSCL, HSDA, LSCL, LSDA	-0.5	3.6	V



### Power Management Integrated Circuit Operating Conditions

Due to the PMIC capability, 5V is the nominal supply to the PMIC from the host through the edge connector pins. The output voltage levels from the PMIC are expected to operate within  $\pm 2.5\%$  in order to satisfy the DRAM voltage requirement range of -3% to +6%.

**Table 11: PMIC 5100 Input Supply Electrical Characteristics**

Parameter	Symbol	Min	Typical	Max	Unit	Notes
Bulk input supply voltage	VIN_Bulk	4.25	5.0	5.5	V	
Bulk input supply maximum – AC voltage	VIN_Bulk_AC	–	–	6.5	V	
Bulk input supply voltage – ramp up rate	VIN_Bulk_Ramp_Up	0.1	–	3.0	V/ms	
Bulk input supply voltage – ramp down rate	VIN_Bulk_Ramp_Down	0.5	–	1.0	V/ms	
Bulk input supply voltage – start up overshoot	VIN_Bulk_OS_Startup	–	–	TBD	V* $\mu$ s	
Maximum input current for VIN_Bulk input supply voltage	I <sub>VIN_Bulk</sub>	0.05	–	2.0	A	
VIN_Bulk Input Quiescent Current	I <sub>VIN_Bulk_Quiescent</sub>	–	–	25	$\mu$ A	
VIN_Bulk Input Idle Current	I <sub>VIN_Bulk_Idle</sub>	–	–	TBD	$\mu$ A	

- Notes: 1. Input supplies referenced in this table are VIN\_BULK and VIN.  
2. During first power-on, the input voltage supply must reach a minimum of 4.25V for the PMIC to detect a valid input supply.  
3. The ramp up rate is between 300mV and 4.0V.  
4. The ramp down rate is between 4.0V and 300mV.  
5. The area under the curve and above VIN\_Bulk = TBD. The VIN\_Bulk\_AC spec must also be satisfied.  
6. The minimum input current requirement is equal to the maximum output current on VOUT\_1.8V and VOUT\_1.0V LDO, plus the current required by the PMIC for its own use. The maximum input current is equal to the all VIN\_Bulk input on the PMIC.  
7. VIN\_Bulk = 5.0V measured at room temperature. All circuitry, including output regulators and LDOs are off. The VR\_EN signal is static LOW or HIGH. The GSI\_n signal is pulled HIGH. I2C or I3C basic interface access is not allowed, and the bus is pulled HIGH. The PID signal is pulled either HIGH or LOW.  
8. VIN\_Bulk = 5.0V measured at room temperature. All output regulators and LDOs are on the 0A output load. The VR\_EN signal is static LOW or HIGH. The GSI\_n signal is pulled HIGH. I2C or I3C basic interface access is not allowed, and the bus is pulled HIGH. The PID signal is pulled either HIGH or LOW.

**Table 12: Absolute Maximum Ratings**

Parameter	Symbol	Min	Max	Unit
Bulk input supply voltage – DC voltage	VIN_Bulk, VIN	-0.3	6.0	V
SWA_FB_P, SWB_FB_P, SWC_FB_P (to AGND) pins	SWA_FB_P, SWB_FB_P, SWC_FB_P	-0.3	2.2	V
PMIC ID pin for I2C and I3C Basic bus	PID	-0.3	2.2	V
SCL, SDA pins (I2C mode only)	SCL, SDA	-0.3	5.0	V
SCL, SDA pins (I3C mode only)	SCL, SDA	-0.3	2.2	V
AGND, PGND pins	AGND, PGND	-0.3	0.3	V



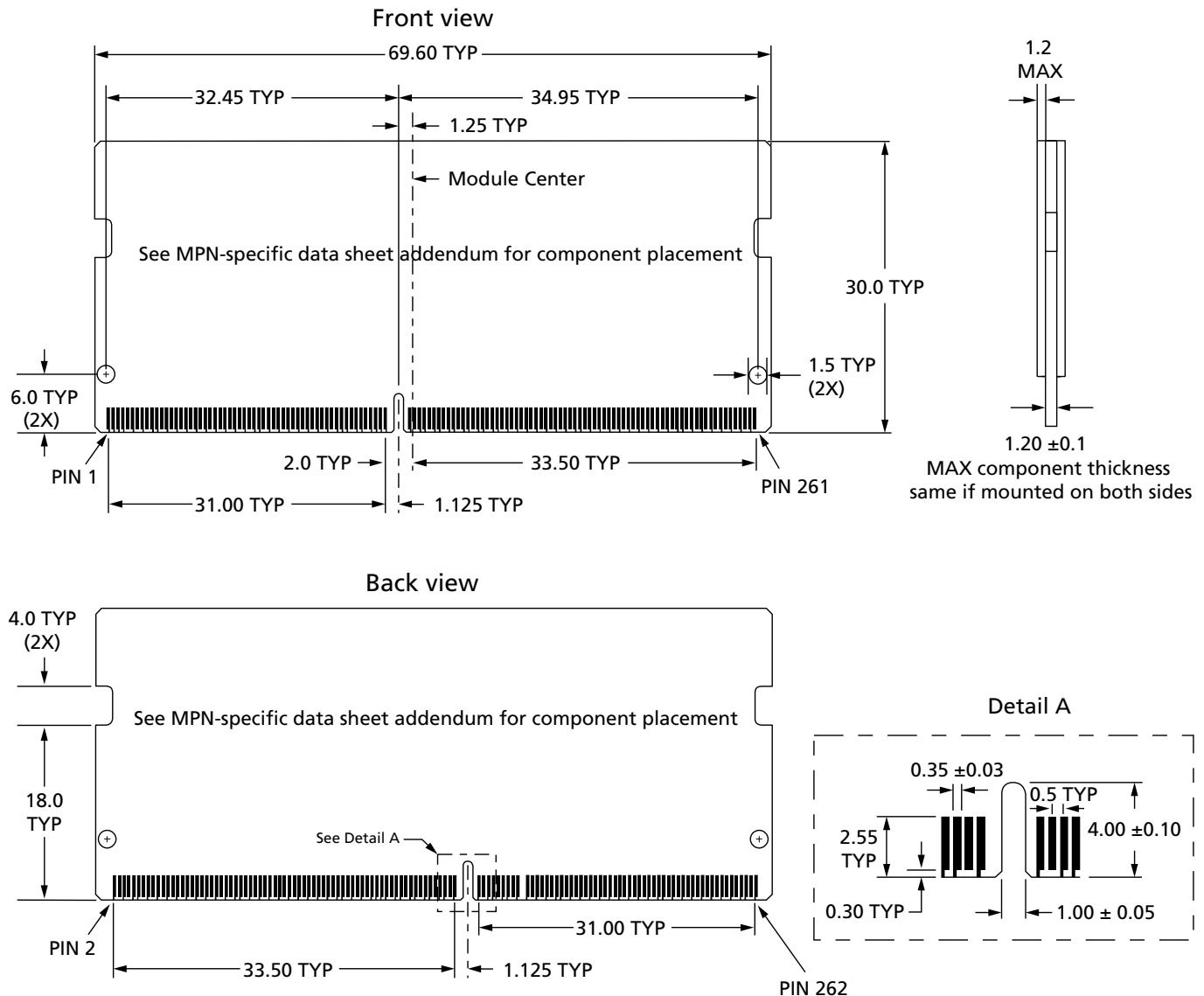
**Table 13: PMIC 5100 Switch Regulator Voltage Output Settings**

Switch Node	Supply	Register	Min	Typ	Max	Unit
SWA	V <sub>DD</sub>	R21[7:1]	1.095	1.1	1.135	V
SWB	V <sub>DD</sub>	R25[7:1]	1.095	1.1	1.135	V
SWC	V <sub>DDQ</sub>	R27[7:1]	1.790	1.8	1.860	V

Notes: 1. Min/Max PMIC output voltage settings are determined based on PMIC output tolerance of  $\pm 2.5\%$  as defined in JESD301-2 in order to ensure the DRAM input voltage specification is met.

## Module Dimensions

**Figure 2: 262-Pin DDR5 SODIMM**



- Notes:
1. All dimensions are in millimeters; MAX/MIN or typical (TYP) where noted.
  2. Tolerance on all dimensions  $\pm 0.15$  unless otherwise specified.
  3. The dimensional diagram is for reference only.

## Revision History

### Rev. E – 10/22

- Remove "Module and Component Speed Bins" table reference. Micron DDR5 Module and Component MPNs use the same part marking.
- Add table to PMIC 5100 Operating Conditions topic for Absolute Maximum Ratings.
- Removed reference to JC 42.2 in SPD Hub Description.
- Added Table to HUB Operating Conditions topic for Absolute Maximum Ratings.
- Converted Speed Grade to Speed Bin in "Key Timing Parameters" table, and corresponding data labels to reflect actual speed bin e.g. 48B to 4800B.
- Changed Speed Grades to Speed Bins in Module and Component Speed Grades (Bins) table under DRAM Operating Conditions.
- Data Transfer Rate range changed to 4800-5600 in Product Family Attributes Table.
- PID Configuration in PMIC Description section - Pin 13 updated to Pin 10.
- Add table to "Power Management Integrated Circuit Operating Conditions" section to specify allowed PMIC output voltage setting range.
- Corrected typo on pin assignment topic pin 20, 22

### Rev. D – 10/2021

- Removed Micron Confidential marking

### Rev. C – 08/2021

- Production Release

### Rev. B – 02/2021

- Preliminary Release

### Rev. A – 07/2020

- Preliminary Release

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This data sheet contains minimum and maximum limits specified over the power supply and temperature range set forth herein. Although considered final, these specifications are subject to change, as further product development and data characterization sometimes occur.